

Notice of References Cited	Application/Control No. 10/613,931*	Applicant(s)/Patent Under Reexamination OIKARI ET AL.	
	Examiner Sharidan Carrillo	Art Unit 1746	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,116,583	05-1992	Batchelder et al.	422/186.07
	B	US-5,227,001	07-1993	Tamaki et al.	156/345.22
	C	US-5,273,060	12-1993	Hill et al.	134/57R
	D	US-6,488,040	12-2002	de Larios et al.	134/95.2
	E	US-6,565,669	05-2003	Bohon, III, Ellis Gray	134/21
	F	US-2002/0102852	08-2002	Verhaverbeke et al.	438/690
	G	US-2002/0170573	11-2002	Christenson et al.	134/2
	H	US-2004/0050406	03-2004	Sehgal, Akshey	134/026
	I	US-2005/0098195	05-2005	Jackson, David P.	134/006
	J	US-2002/0189639	12-2002	Aoki et al.	134/2
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP60003121	01-1985	japan	sato et al.	
	O	DE19611241	09-1997	japan	brunner et al.	
	P	JP06349802	12-1994	japan	nikon corp	
	Q	JP403022427	01-1991	japan	ito et al.	
	R	JP61002316A	01-1986	japan	nec corp	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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